

FORM PTO-1449 (Modified)  
U.S. Department of Commerce, Patent and Trademark Office

Docket No.

CIB-1632A

Serial No.

09/918,395

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

Applicant

Ronald P. Reade et al.

Filing Date

July 30, 2001

Group

Unknown

## U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>PM</i>	AA	6,060,375	5/9/00	Owyang et al.	438	585	7/31/96
<i>PM</i>	AB	5,872,080	2/16/99	Arendt et al.	505	238	4/19/95
<i>PM</i>	AC	5,650,378	7/22/97	Iijima et al.	505	473	8/3/95
<i>PM</i>	AD	5,432,151	7/11/95	Russo et al.	505	474	7/12/93
<i>PM</i>	AE	5,262,394	11/16/93	Wu et al.	505	1	12/27/91
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## Foreign Patent Documents

## Translation

		Document Number	Date	Country	Class	Subclass	Yes	No
<i>PM</i>	AL	01/08169	07/2000	WIPO				
<i>PM</i>	AM	01/08170	07/2000	WIPO				
<i>PM</i>	AN	01/08231	07/2000	WIPO				
<i>PM</i>	AO	01/08232	07/2000	WIPO				
<i>PM</i>	AP	01/08235	07/2000	WIPO				

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>PM</i>	AR	Berdahl, P., et al., "Angular Magnetoresistance Provides Texture Information on High-T <sub>c</sub> Conductors", <u>Physica C</u> , 195, 1992, pp. 93-102.
<i>PM</i>	AS	Bradley, Mark R., et al., "Theory of Thin-Film Orientation by Ion Bombardment during Deposition", <u>J. Appl. Phys.</u> 60 (12), 15 December 1986, pp. 4160-4164.
<i>PM</i>	AT	Dimos, D., et al., "Superconducting Transport Properties of Grain Boundaries in YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7</sub> Bicrystals", <u>Physical Review B</u> , Vol. 41, No. 7, March 1, 1990, pp. 4038-4049.

Examiner

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	BD					
	BE					
	BF					
	BG					
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	BI					
	BJ					
	BK					

## Foreign Patent Documents

							Translation	
	Document Number	Date	Country	Class	Subclass	Yes	No	
<i>gmr</i>	BL 01/08236	07/2000	WIPO	—	—			
<i>gmr</i>	BM 99/16941	09/1998	WIPO	—	—			
<i>gmr</i>	BN 01/08233	07/2000	WIPO	—	—			
<i>gmr</i>	BO 01/26165	07/2000	WIPO	—	—			
<i>gmr</i>	BP 98/58415	06/1998	WIPO	—	—			

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>gmr</i>	BR	Dobrev, D., "Ion-Beam-Induced Texture Formation in Vacuum-Condensed Thin Metal Films", <u>Thin Solid Films</u> 92, 1982, pp. 41-53.
<i>gmr</i>	BS	Fork, D.K., et al., "High Critical Currents in Strained Epitaxial YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-x</sub> on Si", <u>Appl. Phys. Lett.</u> 57 (11), 10 September 1990, pp. 1161-1163.
<i>gmr</i>	BT	Garrison, S.M., et al., "Observation of Two In-Plane Epitaxial States in YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-x</sub> Films on Yttria-Stabilized ZrO <sub>2</sub> ", <u>Appl. Phys. Lett.</u> 58 (19), 13 May 1991, pp. 2168-2170.

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	CA						
	CB						
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	CI						
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Foreign Patent Documents

							Translation	
		Document Number	Date	Country	Class	Subclass	Yes	No
<i>gm</i>	CL	01/15245	07/2000	WIPO	—	—		
<i>gm</i>	CM	01/26164	07/2000	WIPO	—	—		
<i>gm</i>	CN	00/58530	03/2000	WIPO	—	—		
<i>gm</i>	CO	99/17307	09/1998	WIPO	—	—		
<i>gm</i>	CP	01/11428	07/2000	WIPO	—	—		

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>gm</i>	CR	Iijima, Y., et al., "Biaxially Aligned YSZ Buffer Layer on Polycrystalline Substrates", paper prepared for Proceedings of the Fourth International Symposium on Superconductivity, Tokyo, Japan, October 14-17, 1991, pp. 1-4.
<i>gm</i>	CS	Iijima, Y., et al., "In-Plane Aligned YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-x</sub> Thin Films Deposited on Polycrystalline Metallic Substrates", <u>Appl. Phys. Lett.</u> 60 (6), 10 February 1992, pp. 769-771.
<i>gm</i>	CT	Jia, Q.X., et al., "Sputter Deposition of YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-x</sub> Films on Si at 500°C with Conducting Metallic Oxide as a Buffer Layer" <u>Appl. Phys. Lett.</u> 57 (3), 16, July 1990, pp. 304-306.

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Foreign Patent Documents

							Translation	
		Document Number	Date	Country	Class	Subclass	Yes	No
<i>mu</i>	DL	00/58044	01/2000	WIPO				
	DM							
	DN							
	DO							
	DP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>mu</i>	DR	Kumar, Ashok, et al., "Synthesis of Superconducting YBa <sub>2</sub> Cu <sub>3</sub> O <sub>7-x</sub> Thin Films on Nickel-Based Superalloy Using In Situ Pulsed Laser Deposition, <u>Appl. Phys. Lett.</u> 57 (24), 10 December 1990, pp. 2594-2596.
<i>mu</i>	DS	Lioutas, Ch.B., et al., "Phase Transformation of Hydrogen Free Amorphous Carbon Films under Ion Beam Bombardment", <u>Carbon</u> , Vol. 36, No. 5-6, 1998, pp. 545-548.
<i>mu</i>	DT	Mizutani, T., "Compositional and Structural Modifications of Amorphous SiO <sub>2</sub> by Low-Energy Ion and Neutral Beam Irradiation", <u>Journal of Non-Crystalline Solids</u> 181, 1995, pp. 123-134.

Examiner *Forney* Date Considered *7/30/03*

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		Document Number	Date	Country	Class	Subclass	Yes	No
	EL							
	EM							
	EN							
	EO							
	EP							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>me</i>	ER	Narumi, E., et al., "Critical Current Density Enhancement in $\text{YBa}_2\text{Cu}_3\text{O}_{6.8}$ Films on Buffered Metallic Substrates", <u>Appl. Phys. Lett.</u> 58 (11), 18 March 1991, pp. 1202-1204.
<i>me</i>	ES	Norton, David P., et al., "High Critical Current Densities in $\text{YBa}_2\text{Cu}_3\text{O}_{7-x}$ Films on Polycrystalline Zirconia", <u>Appl. Phys. Lett.</u> 57 (11), 10 September 1990, pp. 1164-1166.
<i>me</i>	ET	Pangal, K. et al., "Integration of Amorphous and Polycrystalline Silicon Thin-Film Transistors Through Selective Crystallization of Amorphous Silicon", <u>Appl. Phys. Lett.</u> 75 (14), 4 October 1999, pp. 2091-2093.

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	FA						
	FB						
	FC						
	FD						
	FE						
	FF						
	FG						
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	FJ						
	FK						

## Foreign Patent Documents

							Translation	
		Document Number	Date	Country	Class	Subclass	Yes	No
	FL							
	FM							
	FN							
	FO							
	FP							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>mm</i>	FR	Reade, R.P., et al., "Characterization of Y-Ba-Cu-O Thin Films and Yttria-Stabilized Zirconia Intermediate Layers on Metal Alloys Grown by Pulsed Laser Deposition, <u>Appl. Phys. Lett.</u> 59 (6), 5 August 1991, pp. 739-741.
<i>mm</i>	FS	Reade, R.P., et al., "Laser Deposition of Biaxially Textured Yttria-Stabilized Zirconia Buffer Layers on Polycrystalline Metallic Alloys for High Critical Current Y-Ba-Cu-O Thin Films", <u>Appl. Phys. Lett.</u> 61 (18), 2 November 1992, pp. 2231-2233.
<i>mm</i>	FT	Russo, R.E., et al., "Fabrication and Characterization of Y-Ba-Cu-O Thin-Films on Stainless-Steel Substrates", submitted by authors for publication in <u>High Temperature Superconducting Compounds II</u> , edited by S.H. Whang (Minerals, Metals, and Materials Society, Warrendale), 1990, pp. 1-6.

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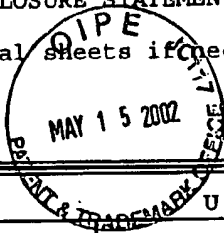
Ronald P. Reade et al.

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							Translation	
		Document Number	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>Mr</i>	AR	Russo, R.E., et al., "Metal Buffer Layers and Y-Ba-Cu-O Thin-Films on Pt and Stainless-Steel Using Pulsed Laser Deposition", <u>J. Appl. Phys.</u> 68 (3), 1 August 1990, pp. 1354-1356.
<i>Mr</i>	AS	Tiwari, P., et al., "In Situ Single Chamber Laser Processing of YBaCuO <sub>1-x</sub> Superconducting Thin Films on Si (100) with Yttria-Stabilized Zirconia Buffer Layers", <u>Appl. Phys. Lett.</u> 57 (15), 8 October 1990, pp. 1578-1580.
<i>Mr</i>	AT	Van Wyk, G.N., "The Dependence of Ion Bombardment Induced Preferential Orientation on the Direction of the Ion Beam", <u>Radiation Effects Letters</u> , Vol. 57, 1980, pp. 45-50.

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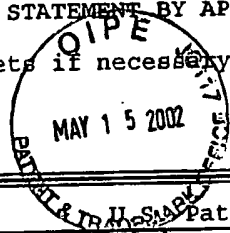
Ronald P. Reade et al.

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Unknown



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	AA						
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	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>[Signature]</i>	AR	Van Wyk, G.N., et al., "Ion Bombardment Induced Preferential Orientation in Polycrystalline Cu Targets", <u>Radiation Effects</u> , Vol. 38, 1978, pp. 245-247.
<i>[Signature]</i>	AS	Wang, C.P. et al., "Deposition of In-Plane Textured MgO on Amorphous Si <sub>3</sub> N <sub>4</sub> Substrates by Ion-Beam-Assisted Deposition and Comparisons with Ion-Beam-Assisted Deposited Yttria-Stabilized-Zirconia", <u>Appl. Phys. Lett.</u> 71 (20), 17 November 1997, pp. 2955-2957.
<i>[Signature]</i>	AT	Wiesmann, J., et al., "Large-Area Deposition of Biaxially Textured YSZ Buffer Layers Using an IBAD-Process", <u>Nucl. Instr. and Meth. in Phys. Res. B</u> 120, 1996, pp. 290-292.

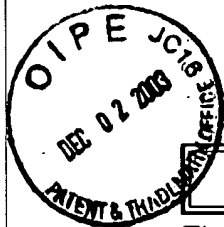
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# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

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## Title of Invention

ION TEXTURING METHODS AND ARTICLES

Application Number: 09/918395  
Confirmation Number: 9970  
First Named Applicant: RONALD READE  
Attorney Docket Number: IB-1632A  
Art Unit: 1753  
Examiner: RODNEY GLENN MCDONALD  
Search string: ( 6258472 or 6190752 or 6498549 or 6537689  
or 5246741 or 4776925 or 5607781 or 5601654  
or 6033471 or 5372089 or 20020017235 or  
20020041973 or 20010006042 ).pn.

## US Patent Documents

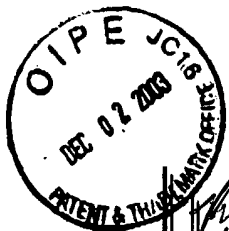
Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
<input checked="" type="checkbox"/>	1	6258472	2001-07-10	Neumuller et al.	B1	428	701
<input type="checkbox"/>	2	6190752	2001-02-20	Do et al.	B1	428	141
<input type="checkbox"/>	3	6498549	2002-12-24	Jiang et al.	B1	333	202
<input type="checkbox"/>	4	6537689	2003-03-25	Schoop et al.	B2	428	701
<input type="checkbox"/>	5	5246741	2003-09-21	Ouhata et al.	B1	427	524
<input type="checkbox"/>	6	4776925	1988-10-11	Fossum et al.	B1	428	297
<input type="checkbox"/>	7	5607781	1997-03-04	Okuno et al.	B1	110	723HE
<input type="checkbox"/>	8	5601654	1997-02-11	Springer	B1	428	694ML
<input type="checkbox"/>	9	6033471	2000-03-07	Nakanishi et al.	B1	117	108
<input checked="" type="checkbox"/>	10	5372089	1994-12-13	Yoshida et al.	B1	117	98

## US Published Applications

Note: Applicant is not required to submit a paper copy of cited US Published Applications

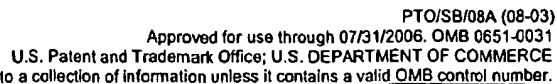
init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
<input type="checkbox"/>							



<i>[initials]</i>	1	20020017235	2002-02-14	Nagasaka et al.	A1	117 106
<i>[initials]</i>	2	20020041973	2002-04-11	Belouet	A1	428 623
<i>[initials]</i>	3	20010006042	2001-07-05	Iijima et al.	A1	118 718

Signature

Examiner Name	Date
<i>Rodney McDonald</i>	4/12/04



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Substitute for form 1449/PTO

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Sheet	1	of	1
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**Complete if Known**

Application Number	09/918,395
Filing Date	07/30/2001
First Named Inventor	Ronald P. Reade
Art Unit	1753
Examiner Name	Rodney G. McDonald
Attorney Docket Number	IB-1632A

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## U. S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T <sup>2</sup>
		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	MM-DD-YYYY			
<i>mu</i>		JP 01215966 A	09/1989	Yamaki et al.	<del>_____</del>	

Examiner Signature	<i>Robert M. Bernal</i>	Date Considered	4/12/04
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